Test Org.*	Device	Function	Technology	Mfr.	Effective SEU LET* Threshold	Device Xsection (cm^2)	Bits Tested	Bit Xsection (cm^2)	Test Date	LUth	LU Xsection (cm^2)	Fac.	Remarks 23-Aug-99
		Microprocessor (4-bit)											
	Note: Entries in **RED** indicate data added since the 1997 Compendium.												
JPL/ARSP	2901		CMOS with R=80 Kohms	SNL	>100		64					UCB	
JPL/ARSP	2901		CMOS with no register	SNL	>100		64					UCB	
JPL	2901A		Bipolar- LSTTL	AMD	~7	5.0E-03	64	8.0E-05				UCB	
JPL	2901-A1		Bipolar?	NSC	<3.3	1.0E-03	64	2.0E-05				UCB	27 MeV Carbon
JPL	2901-A2		Bipolar?	NSC	<3.3	1.0E-03	64	2.0E-05				UCB	27 MeV Carbon
JPL	2901-AX		Bipolar?	NSC	<3.3	1.0E-03	64	2.0E-05				UCB	27 MeV Carbon
JPL	2901B		Bipolar- LSTTL	AMD	~4	3.0E-03	64	5.0E-05				UCB	
ARSP	2901B		Bipolar- LSTTL	AMD	4	3.0E-04	64	5.0E-06				UCB	Test of RAM, Q-Reg., ALU & two latches.
JPL	2901C		Bipolar/ECL	AMD	<<3.3	3.0E-03	64	5.0E-05				UCB	
ARSP	2901C		Bipolar/ECL	AMD	<8	5.0E-04	64	8.0E-06				UCB	Test like AMD 2901B.
JPL	29F01		Bipolar-FAST	FAS	<6	3.0E-04	64	5.0E-06				UCB	26 MeV oxygen
ARSP	AMAS2901		CMOS/SOS	GPS	>120				1994			UCB	Koga
ARSP	AMAS2901FB		CMOS	PLS	>120					>120		UCB	Koga

Legend

Manufacturers: ATM - Atmel; CYP - Cypress; HTC - Hitachi; INT - Intel; NEC - Nippon Electric Corp; MIT -Mitsubishi; SGS - Silicon General; TIX - Texas Instruments; TOS - Toshiba; WAF - Waferscale

Test Organizations

ARSP - Aerospace Corp., El Segundo, CA

JPL - Jet Propulsion Laboratory, Pasadena, CA

Radiation Test Facilities

UCB - 88-inch Cyclotron, University of California, Berkeley, CA